

Application/Control	No.
10/634.416	

Examiner Bryan Bui Applicant(s)/Patent under Reexamination

PATE ET AL.

2863

	INTERNATIONAL CLASSIFICATION													
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(Assistant Examiner) (Date)							NEF		Total Claims Allowed: 27					
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С	Claims renumbered in the same order as presented by applicant									□СРА			□ T.D.		☐ R.1.47				
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
1	1			31			61			91			121			151			181
2	2			32			62			92			122			152			182
3	3			33			63			93			123			153			183
4	4			34			64			94			124	.		154			184
5	5			35			65			95			125			155			185
6	6			36			66] `		96			126			156			186
7	7			37			67]		97			127			157			187
8	8			38			68	Ì		98			128			158			188
9	9			39			69			99			129			159			189
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11	11	ì		41			71			101			131			161			191
12	12			42			72			102			132			162			192
13	13]		43		-	73			103			133			163			193
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15	15			45			75			105			135			165			195
16	16	ĺ		46			76		-	106			136			166			196
17	17	1		47			77			107	•		137			167			197
18	18	1		48			78			108			138			168			198
19	19	İ		49	1		79			109			139			169			199
20	20	1		50			80			110			140			170·			200
21	21	1		51	1		81			111			141			171			201
22	22	1		52			82			112			142			172			202
23	23	1		53	1		83	1		113			143			173			203
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25	25	1		55	1		85	1		115			145]		175			205
26	26	1		56	1.		86	1		116			146]		176			206
27	27	1		57	1		87	1		117			147			177			207
	28	1		58	1		88	1		118			148	1		178			208
	29	1		59	1		89	1		119			149]		179			209
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